

Search Notes



Application No.

10/662.830

Examiner

Ernest F. Karlsen

Applicant(s)

HOLLMAN, KENNETH F.

Art Unit

2829

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

ITEM	DATE	EXMR
conductive adj path and indicia electron adj microscope and semiconductor and test and imag\$ and probe\$	6/25/2004	EJK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
324	758 751 762	6/25/2004	E.P.K.